

RF Exposure Report

Report No.: SABEMI-WTW-P20080078

FCC ID: NOI-H3750B

Test Model: H3750B

Received Date: 2021/8/6

Test Date: 2021/10/4

Issued Date: 2021/11/12

Applicant: NETRONIX, INC.

Address: No 945, Boai St, Jubei City, Hsinchu, 30265 Taiwan

Issued By: Bureau Veritas Consumer Products Services (H.K.) Ltd., Taoyuan Branch
Hsin Chu Laboratory

Lab Address: E-2, No.1, Li Hsin 1st Road, Hsinchu Science Park, Hsinchu City 300,
Taiwan

Test Location: E-2, No.1, Li Hsin 1st Road, Hsinchu Science Park, Hsinchu City 300,
Taiwan

**FCC Registration /
Designation Number:** 723255 / TW2022



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Release Control Record

Issue No.	Description	Date Issued
SABEMI-WTW-P20080078	Original release.	2021/11/12

1 Certificate of Conformity

Product: Electronic Bag Tag (EBT)

Brand: NETRONIX, BAGTAG

Test Model: H3750B

Sample Status: Engineering sample

Applicant: NETRONIX, INC.

Test Date: 2021/10/4

Standards: FCC Part 2 (Section 2.1093)

KDB 447498 D01 General RF Exposure Guidance v06

The above equipment has been tested by **Bureau Veritas Consumer Products Services (H.K.) Ltd., Taoyuan Branch**, and found compliance with the requirement of the above standards. The test record, data evaluation & Equipment Under Test (EUT) configurations represented herein are true and accurate accounts of the measurements of the sample's EMC characteristics under the conditions specified in this report.

Prepared by : Vivian Huang , **Date:** 2021/11/12
Vivian Huang / Specialist

Approved by : Clark Lin , **Date:** 2021/11/12
Clark Lin / Technical Manager

2 Evaluation Result

Following FCC KDB 447498 D01 “General SAR test exclusion guidance”

The corresponding SAR Exclusion Threshold condition, listed below:

- 1) The 1-g and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:
$$\left[\frac{\text{max. power of channel, including tune-up tolerance, mW}}{\text{min. test separation distance, mm}} \right] \cdot [\sqrt{f(\text{GHz})}]$$
$$\leq 3.0 \text{ for 1-g SAR and } \leq 7.5 \text{ for 10-g extremity SAR, where}$$
 - $f(\text{GHz})$ is the RF channel transmit frequency in GHz.
 - Power and distance are rounded to the nearest mW and mm before calculation.
 - The result is rounded to one decimal place for comparison. The test exclusions are applicable only when the minimum test separation distance is ≤ 50 mm and for transmission frequencies between 100 MHz and 6 GHz. When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.
- 2) At 100 MHz to 6 GHz and for test separation distances > 50 mm, the SAR test exclusion threshold is determined according to the following:
 - a) [Threshold at 50 mm in step 1) + (test separation distance - 50mm) · ($f(\text{MHz})/150$)] mW, at 100MHz to 1500 MHz
 - b) [Threshold at 50 mm in step 1) + (test separation distance - 50 mm) · 10] mW at > 1500 MHz and ≤ 6 GHz
- 3) At frequencies below 100 MHz, the following may be considered for SAR test exclusion.
 - a) The threshold at the corresponding test separation distance at 100 MHz in step 2) is multiplied by $[1 + \log(100/f(\text{MHz}))]$ for test separation distances > 50 mm and < 200 mm.
 - b) The threshold determined by the equation in a) for 50 mm and 100 MHz is multiplied by $\frac{1}{2}$ for test separation distances ≤ 50 mm.
 - c) SAR measurement procedures are not established below 100 MHz. When SAR test exclusion cannot be applied, a KDB inquiry is required to determine SAR evaluation requirements for any test results to be acceptable.

3 SAR Test Exclusion Thresholds

BT-LE Avg. Power Table

BT-LE 1M

Channel	Frequency (MHz)	Average Power (mW)	Average Power (dBm)
0	2402	0.03597	-14.44
19	2440	0.03034	-15.18
39	2480	0.0507	-12.95

BT-LE 2M

Channel	Frequency (MHz)	Average Power (mW)	Average Power (dBm)
0	2402	0.07129	-11.47
19	2440	0.1219	-9.14
39	2480	0.1045	-9.81

For BT-LE SAR Test Exclusion Thresholds

Frequency (MHz)	Max Avg. Power (dBm)	Max Avg. Power (mW)	Min. test separation distance (mm)	SAR test exclusion calculation value ^(NOTE 1)	10-g SAR test exclusion thresholds	Result
2402 ~ 2480	-9.14	0.1219	5	0.0384	7.5	Pass

Note: 1. Calculate SAR test exclusion thresholds from condition "1" formulas.

4 Conclusion

Since average power is below SAR test exclusion power thresholds, the SAR evaluation is not required.

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